

Search Notes

Application/Control No.

10/730,636

Examiner

Donghee Kang

Applicant(s)/Patent under
Reexamination

PEICHL ET AL.

Art Unit

2811

SEARCHED

Class	Subclass	Date	Examiner
257	458-466	11/2/2004	KANG
438	48,89,98	11/2/2004	KANG
UPDATED	SEARCH	7/12/2005	KANG

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
257	458-460	7/13/2005	KANG
257	465-466	7/13/2005	KANG
438	48,89,98	7/13/2005	KANG

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST USPAT,USOCR,USPGPUB,EPO,JPO ,DEW,IBMTDB	11/2/2004	KANG
TEXT SEARCH SEE ATTACHED SEARCH HISTORY	11/2/2004	KANG
TEXT SEARCH SEE ATTACHED SEARCH HISTORY	7/12/2005	KANG
NPL IEEE EXPLORE, J. APPL. OPTICS, J. OF APPL. PHYS. PHYS. LETT.	7/13/2005	KANG